

Category: Hardware & Devices, Home & Family, Productivity & Work, Operating Systems Category: Operating system
Molecular biology of astrocytomas. The development of astrocytoma in humans may involve genetic and/or epigenetic alterations. However, the molecular mechanisms that lead to astrocytoma development remain largely unknown. To understand better the pathogenesis of astrocytoma, the most common type of primary brain tumor, the authors determined the presence and molecular characterization of the t(11;14) translocation in 29 human astrocytomas. To analyze the 11q14-q23 region, the authors used Southern hybridization, fluorescence in situ hybridization (FISH), and oligonucleotide-based microarrays. In addition, the authors analyzed the methylation status of the promoter regions of selected tumor suppressor genes. The presence of a translocation t(11;14) was confirmed in 23 astrocytomas, and all of these tumors had a characteristic G-C oligonucleotide content. One astrocytoma had a t(12;14) and another had a t(14;22). The presence of a translocation was positively correlated with grade (less differentiated astrocytoma > anaplastic astrocytoma). As the 11q13.3-q14.1 region, which contains the CHOP gene, has been implicated in the development of a variety of human tumors, the authors also examined its methylation status in astrocytomas. Promoter hypermethylation was associated with the presence of the translocation. The data suggest that the t(11;14) translocation, in conjunction with gene methylation, may play a role in the pathogenesis of astrocytomas.
Q: Efficient way to get a hash out of an array In a script I'm doing in Perl, I have an array @out that has been generated by a subroutine. sub generate_out { my @out = (); foreach \$item (@input) { my @a = @\$item; @out = ("a" x @a); } return @out; } I want to get a hash out of it. I've done it before in

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1. Field of the Invention The present invention relates to a shift register used in an LCD driver, which is connected to a LCD panel to drive the panel. 2. Description of Related Art In an LCD driver, a shift register is used to select a scan line of the LCD panel in a scanning operation. The shift register selects each pixel line of a frame at a time, from the frame start to the frame end. The frame start is defined by the start signal from the scanning circuit and the start signal from the timing circuit. The frame end is defined by the end signal from the timing circuit. A test mode signal is an internal signal from the timing circuit to the shift register. In a conventional circuit design, the shift register is coupled to the timing circuit through a T/R switch circuit. The T/R switch circuit is controlled by the test mode signal, and the T/R switch circuit is either an open circuit or a closed circuit to couple the shift register to the timing circuit. However, in this design, the test mode signal is an external signal from a timing control circuit. Therefore, the signal will be changed at the time of the change of the timing control circuit. Accordingly, an object of the invention is to provide a shift register that can be controlled by the internal signal from the timing circuit to avoid the change of the test mode signal. To achieve these and other advantages and in accordance with the purpose of the invention, as embodied and broadly described herein, the invention provides a shift register circuit. The shift register circuit includes a test mode signal, a test signal, a test mode control circuit, a clock signal, a driver, a driver control circuit, a test circuit, and a shift register. The test mode signal is a first voltage. The test mode signal is a low voltage at the time of testing and a high voltage at the time of normal operation. The driver is a first transistor with a source coupled to a power supply. The driver control circuit receives the test mode signal, and controls the driver. The test circuit is coupled to the driver and the driver control circuit. The test circuit is a second transistor, and the gate of the second transistor is coupled to the source of the first transistor. The shift register is coupled to the test circuit. The shift register includes a first transistor with a source coupled to a power supply 2d92ce491b